

PRESS RELEASE

Andreas Breyer
Manager Media Relations

for immediate release

Mobile +49 151 1242 8585
E-Mail press@emva.org

05 September, 2019

EMVA organizes Machine Vision Presentation Forum during Measurement World Exhibition in Paris

- *Series of speeches on machine vision topics during first two trade show days*
- *Several EMVA member companies exhibit with their own booth*

Barcelona/Paris, 05 September, 2019. EMVA is pleased to announce that it will contribute to the machine vision presence during the exhibition Measurement World with a presentation forum. The new biannual exhibition format Measurement World is dedicated to measurement in its broadest sense and takes place from September 24 – 26 in hall 4 at Paris Expo Port de Versailles. The machine vision presentations are given in French or English and free of charge for all visitors and will be held on Tuesday, 24 September from 2.00 pm – 5.00 pm and on Wednesday, 25 September from 9.30 am – 12.00 pm in ROOM 1 of hall 4.

Presentation topics include state of the art vision technology; the description of concrete machine vision applications in different industrial sectors; machine vision standards and their objectives as well as the description of the vision markets in France, in Europe and worldwide. Below the timetable including the presentation titles:

Tuesday, 24 September

14:00 – 14:30	EMVA: Presentation and numbers Jean CARON – Michel OLLIVIER – Members of the EMVA Board
14:30 – 15:00	State of the art of visible Machine Vision sensors Yvan EILERS - SVS-VISTEK
15:00 - 15:30	Artificial Intelligence on edge devices for machine vision applications Boris DUCHE - IDS
15:30 – 16:00	Illumination techniques for new vision applications (Hyperspectral, SWIR, 3D...) Arnaud MESTIVIER – EFFILUX
16:00 – 16:30	How to use the Sony polarized camera technology for complex applications and open new fields for inspection? Pascal CHEVALIER – I2S / Stéphane CLAUSS – SONY
16:30 – 17:00	Embedded vision : from optimization to miniaturization, key factors to succeed in the development of your applications Elodie Rigaudiere / TECHWAY

Wednesday, 25 September

9:30 – 10:00	EMVA: Machine Vision standards Jean CARON – Michel OLLIVIER – Members of the EMVA Board
10:00 – 10:30	Multiple object tracking, a challenge for machine vision Romain BAUDE – APREX SAS
10:30 - 11:00	How to innovate and create value with public research? Rodolphe BERNARD – INSAVALOR
11:00 – 11:30	Expand the reach of your inspection systems with infrared imaging technologies Sébastien FRASSE-SOMBET – LYNRED (SOFRADIR/ULIS)
11:30 – 12:00	XRAY tomography services the industrial world Laura CREON - SEMATEC

EMVA members at Measurement World

Several EMVA members will exhibit at Measurement World with their own booths. These are ATD Electronique, Carl Zeiss, Edmund Optics GmbH, EFFILUX, IDS – Imaging Development Systems, Mettler Toledo, Precitec, Stemmer Imaging, SVS Vistek, and VS Technology. Furthermore, in addition to their trade fair booth ATD Electronique announced that the company offers its own conference program. More details on the program and how to register can be found on their websites www.atdelectronique.com/event-shows.

About EMVA:

Founded in May 2003 in Barcelona, the European Machine Vision Association currently has about 120+ members representing more than 20 nations. Its aim is to promote the development and use of machine vision technology and to support the interests of its members - machine vision companies, research institutions and national machine vision associations. The main fields of work of EMVA are: standardization, statistics, the annual EMVA Business Conference and other networking events, European research funding, public relations and marketing. To find out more visit the web site www.emva.org.